Se	arch	Notes	

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/535,371	HOWLEY ET AL.	
Examiner	Art Unit	
Sharon Hurt	1648	

	SEARCHED		
Class	Subclass	Date	Examiner
	<u>-</u> -		

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
	<u> </u>		

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
EDAN: Inventor Search: Howley and Leyer	12/7/2006	SH
STN: BIOSIS: see attached	12/7/2006	SH
PUBMED: see attached	12/7/2006	SH
STIC: sequence search: SEQ ID NO:1: results in EDAN	12/5/2006	SH
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